



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN# 20240508001.1

**Qualification of RFAB using qualified Process Technology, Die Revision and
additional Assembly site/BOM options for select devices
Change Notification / Sample Request**

Date: May 08, 2024
To: Mouser PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

Texas Instruments requires acknowledgement of receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance and approval of this change. If samples or additional data are required, requests must be received within **30 days** of this notification.

The changes discussed within this PCN will not take effect any earlier than the proposed first ship date on Page 3 of this notification, unless customer agreement has been reached on an earlier implementation of the change.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the change management team.

For sample requests or sample related questions, contact your local Field Sales Representative.

Sincerely,

Change Management Team
SC Business Services

20240508001.1
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, you have recently purchased these devices. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
TMP102AIDRLR	NULL
TMP1075NDRLR	NULL
TMP112AIDRLR	NULL
TMP112BIDRLR	NULL
TMP112NAIDRLR	NULL

Technical details of this Product Change follow on the next page(s).

PCN Number:	20240508001.1	PCN Date:	May 08, 2024
Title:	Qualification of RFAB using qualified Process Technology, Die Revision and additional Assembly site/BOM options for select devices		
Customer Contact:	Change Management Team	Dept:	Quality Services
Proposed 1st Ship Date:	August 06, 2024	Sample requests accepted until:	June 07, 2024*
*Sample requests received after June 07, 2024 will not be supported.			
Change Type:			
<input checked="" type="checkbox"/> Assembly Site	<input checked="" type="checkbox"/> Design	<input type="checkbox"/>	Wafer Bump Material
<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Data Sheet	<input type="checkbox"/>	Wafer Bump Process
<input checked="" type="checkbox"/> Assembly Materials	<input type="checkbox"/> Part number change	<input checked="" type="checkbox"/>	Wafer Fab Site
<input type="checkbox"/> Mechanical Specification	<input type="checkbox"/> Test Site	<input checked="" type="checkbox"/>	Wafer Fab Material
<input checked="" type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process	<input checked="" type="checkbox"/>	Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab option in addition to a new Assembly site (TIPI) for the devices listed in the "Product Affected" section.

Current Fab Site			Additional Fab Site		
Fab Site	Process	Wafer Diameter	Fab Site	Process	Wafer Diameter
AIZU	HPA07	200 mm	RFAB	LBC9	300 mm

The die was also changed as a result of the process change.

Construction differences are as follows:

Group 1 Device

	Current	Proposed
Wire diam/type	0.8mil Au	0.8mil Cu

Group 2 Device

	HNA	TIPI
Wire diam/type	0.8mil Au	0.8mil Cu
Mount compound	400194	4226215
Mold compound	450214	4222198

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings:

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
<input checked="" type="checkbox"/> No Change			

Changes to product identification resulting from this PCN:

Fab Site Information:	Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City

AIZU RFAB	CU2 RFB	JPN USA	Aizuwakamatsu-shi Richardson
---------------------	-------------------	-------------------	--

Die Rev:

Current

New

Die Rev [2P]	Die Rev [2P]
E	A

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
HNA	HNT	THA	Ayutthaya
TIPI	PHI	PHL	Baguio City

Sample product shipping label (not actual product label):



Product Affected:

Group 1 Device (Wafer fab, Die rev, BOM)

SN1608035DRLR	TMP102AIDRLR	TMP112AIDRLR
SN1710027DRLR	TMP1075NDRLR	

Group 2 Device (Wafer fab, Die rev, Assembly site)

TMP112BIDRLR	TMP112NAIDRLR
--------------	---------------

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: TMP112AIDRLR (PG1.0)	Qual Device: TMP112BIDRLR	Qual Device: TMP112NAIDRLR	Qual Device: SN1608035DRLR	Qual Device: TMP112AIDRLR(PGL1)	QBS Reference: SN74AXC1T45DRLR-S	QBS Reference: TMP350A0DRLRQ1	QBS Reference: LM33LVQDYYRQ1	QBS Reference: TPD2E1B06DRLR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	3/231/0	3/231/0	1/77/0	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	3/231/0	3/231/0	1/77/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	3/231/0	1/77/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	3/231/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	-	-	-	-	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	3/231/0	1/77/0	-
ESD	E2	ESD CDM	-	1000 Volts	1/3/0	-	-	-	-	-	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-	1/3/0	-	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/3/0	-	-	-	1/3/0	-	-	-	-

- QBS: Qual By Similarity
- Qual Device TMP112AIDRLR is qualified at MSL1 260C
- Qual Device TMP112BIDRLR is qualified at MSL1 260C
- Qual Device TMP112NAIDRLR is qualified at MSL1 260C
- Qual Device SN1608035DRLR is qualified at MSL1 260C
- Qual Device TMP112AIDRLR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-NPD-2302-155

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: TMP1075NDRLR	QBS Reference: SN74AXC1T45DRLRS	QBS Reference: TMP390AQDRLRQ1	QBS Reference: LM339LVQDYYRQ1	QBS Reference: TPD2E1B06DRLR	QBS Reference: TMP112AIDRLR(PG1.1)
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	1/77/0	3/231/0	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0	1/77/0	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	1/77/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/231/0	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	1/77/0	-	-
ESD	E2	ESD CDM	-	1000 Volts	1/3/0	-	-	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	-	1/30/0

- QBS: Qual By Similarity
- Qual Device [TMP1075NDRLR](#) is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-NPD-2312-006

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: TMP102AIDRLR	Qual Device: SN1710027DRLR	QBS Reference: SN74AXC1T45DRLRS	QBS Reference: TMP390AQDRLRQ1	QBS Reference: LM339LVQDYYRQ1	QBS Reference: TPD2E1B06DRLR	QBS Reference: TMP112AIDRLR(PG1.1)
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	3/231/0	1/77/0	3/231/0	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	3/231/0	1/77/0	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	1/77/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/231/0	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	-	3/231/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	1/77/0	-	-
ESD	E2	ESD CDM	-	1000 Volts	1/3/0	-	-	-	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	-	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-	-	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	-	-	1/30/0

- QBS: Qual By Similarity
- Qual Device [TMP102AIDRLR](#) is qualified at MSL1 260C
- Qual Device [SN1710027DRLR](#) is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

TI Qualification ID: R-NPD-2302-154

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.